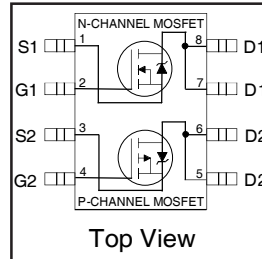


# IRF9952QPbF

HEXFET® Power MOSFET

- Advanced Process Technology
- Ultra Low On-Resistance
- Dual N and P Channel MOSFET
- Surface Mount
- Available in Tape & Reel
- 150°C Operating Temperature
- Lead-Free

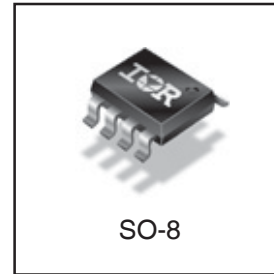


	N-Ch	P-Ch
$V_{DS}$	30V	-30V
$R_{DS(on)}$	0.10 $\Omega$	0.25 $\Omega$

## Description

These HEXFET® Power MOSFET's in a Dual SO-8 package utilize the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of these HEXFET Power MOSFET's are a 150°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These benefits combine to make this design an extremely efficient and reliable device for use in a wide variety of applications.

The efficient SO-8 package provides enhanced thermal characteristics and dual MOSFET die capability making it ideal in a variety of power applications. This dual, surface mount SO-8 can dramatically reduce board space and is also available in Tape & Reel.



	Symbol	Maximum		Units	
		N-Channel	P-Channel		
Drain-Source Voltage	$V_{DS}$	30		V	
Gate-Source Voltage	$V_{GS}$	$\pm 20$			
Continuous Drain Current <sup>⑤</sup>	$I_D$	$T_A = 25^\circ\text{C}$	3.5	-2.3	A
		$T_A = 70^\circ\text{C}$	2.8	-1.8	
Pulsed Drain Current	$I_{DM}$	16	-10		
Continuous Source Current (Diode Conduction)	$I_S$	1.7	-1.3		
Maximum Power Dissipation <sup>⑤</sup>	$P_D$	$T_A = 25^\circ\text{C}$	2.0		W
		$T_A = 70^\circ\text{C}$	1.3		
Single Pulse Avalanche Energy	$E_{AS}$	44	57	mJ	
Avalanche Current	$I_{AR}$	2.0	-1.3	A	
Repetitive Avalanche Energy	$E_{AR}$	0.25		mJ	
Peak Diode Recovery $dv/dt$ <sup>②</sup>	$dv/dt$	5.0	-5.0	V/ ns	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to + 150		$^\circ\text{C}$	

## Thermal Resistance Ratings

Parameter	Symbol	Limit	Units
Maximum Junction-to-Ambient <sup>⑤</sup>	$R_{\theta JA}$	62.5	$^\circ\text{C/W}$

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## Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

Parameter	Parameter	Min.	Typ.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	N-Ch 30 P-Ch -30	—	—	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA V <sub>GS</sub> = 0V, I <sub>D</sub> = -250μA
ΔV <sub>(BR)DSS</sub> /ΔT <sub>J</sub>	Breakdown Voltage Temp. Coefficient	N-Ch — P-Ch —	0.015 0.015	—	V/°C	Reference to 25°C, I <sub>D</sub> = 1mA Reference to 25°C, I <sub>D</sub> = -1mA
R <sub>DS(ON)</sub>	Static Drain-to-Source On-Resistance	N-Ch — P-Ch —	0.08 0.12	0.10 0.15	Ω	V <sub>GS</sub> = 10V, I <sub>D</sub> = 2.2A ④ V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 1.0A ④ V <sub>GS</sub> = -10V, I <sub>D</sub> = -1.0A ④ V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -0.50A ④
V <sub>GS(th)</sub>	Gate Threshold Voltage	N-Ch 1.0 P-Ch -1.0	—	—	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250μA
g <sub>fs</sub>	Forward Transconductance	N-Ch — P-Ch —	12 2.4	—	S	V <sub>DS</sub> = 15V, I <sub>D</sub> = 3.5A ④ V <sub>DS</sub> = -15V, I <sub>D</sub> = -2.3A ④
I <sub>DSS</sub>	Drain-to-Source Leakage Current	N-Ch — P-Ch —	—	2.0 -2.0	μA	V <sub>DS</sub> = 24V, V <sub>GS</sub> = 0V V <sub>DS</sub> = -24V, V <sub>GS</sub> = 0V
I <sub>GSS</sub>	Gate-to-Source Forward Leakage	N-P —	—	±100	nA	V <sub>GS</sub> = ±20V
Q <sub>g</sub>	Total Gate Charge	N-Ch — P-Ch —	6.9 6.1	14 12	nC	N-Channel I <sub>D</sub> = 1.8A, V <sub>DS</sub> = 10V, V <sub>GS</sub> = 10V ④
Q <sub>gs</sub>	Gate-to-Source Charge	N-Ch — P-Ch —	1.0 1.7	2.0 3.4	nC	P-Channel I <sub>D</sub> = -2.3A, V <sub>DS</sub> = -10V, V <sub>GS</sub> = -10V ④
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge	N-Ch — P-Ch —	1.8 1.1	3.5 2.2	nC	
t <sub>d(on)</sub>	Turn-On Delay Time	N-Ch — P-Ch —	6.2 9.7	12 19	ns	N-Channel V <sub>DD</sub> = 10V, I <sub>D</sub> = 1.0A, R <sub>G</sub> = 6.0Ω, R <sub>D</sub> = 10Ω ④
t <sub>r</sub>	Rise Time	N-Ch — P-Ch —	8.8 14	18 28	ns	
t <sub>d(off)</sub>	Turn-Off Delay Time	N-Ch — P-Ch —	13 20	26 40	ns	P-Channel V <sub>DD</sub> = -10V, I <sub>D</sub> = -1.0A, R <sub>G</sub> = 6.0Ω, R <sub>D</sub> = 10Ω ④
t <sub>f</sub>	Fall Time	N-Ch — P-Ch —	3.0 6.9	6.0 14	ns	
C <sub>iss</sub>	Input Capacitance	N-Ch — P-Ch —	190 190	—	pF	N-Channel V <sub>GS</sub> = 0V, V <sub>DS</sub> = 15V, f = 1.0MHz
C <sub>oss</sub>	Output Capacitance	N-Ch — P-Ch —	120 110	—	pF	P-Channel V <sub>GS</sub> = 0V, V <sub>DS</sub> = -15V, f = 1.0MHz
C <sub>rss</sub>	Reverse Transfer Capacitance	N-Ch — P-Ch —	61 54	—	pF	

## Source-Drain Ratings and Characteristics

Parameter	Parameter	Min.	Typ.	Max.	Units	Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)	N-Ch — P-Ch —	—	1.7 -1.3	A	
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①	N-Ch — P-Ch —	—	16 16	A	
V <sub>SD</sub>	Diode Forward Voltage	N-Ch — P-Ch —	0.82 -0.82	1.2 -1.2	V	T <sub>J</sub> = 25°C, I <sub>S</sub> = 1.25A, V <sub>GS</sub> = 0V ③ T <sub>J</sub> = 25°C, I <sub>S</sub> = -1.25A, V <sub>GS</sub> = 0V ③
t <sub>rr</sub>	Reverse Recovery Time	N-Ch — P-Ch —	27 27	53 54	ns	N-Channel T <sub>J</sub> = 25°C, I <sub>F</sub> = 1.25A, di/dt = 100A/μs ④
Q <sub>rr</sub>	Reverse Recovery Charge	N-Ch — P-Ch —	28 31	57 62	nC	P-Channel T <sub>J</sub> = 25°C, I <sub>F</sub> = -1.25A, di/dt = 100A/μs ④

### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 23 )
- ② N-Channel I<sub>SD</sub> ≤ 2.0A, di/dt ≤ 100A/μs, V<sub>DD</sub> ≤ V<sub>(BR)DSS</sub>, T<sub>J</sub> ≤ 150°C  
P-Channel I<sub>SD</sub> ≤ -1.3A, di/dt ≤ 84A/μs, V<sub>DD</sub> ≤ V<sub>(BR)DSS</sub>, T<sub>J</sub> ≤ 150°C
- ③ N-Channel Starting T<sub>J</sub> = 25°C, L = 22mH R<sub>G</sub> = 25Ω, I<sub>AS</sub> = 2.0A. (See Figure 12)  
P-Channel Starting T<sub>J</sub> = 25°C, L = 67mH R<sub>G</sub> = 25Ω, I<sub>AS</sub> = -1.3A.
- ④ Pulse width ≤ 300μs; duty cycle ≤ 2%.
- ⑤ Surface mounted on FR-4 board, t ≤ 10sec.

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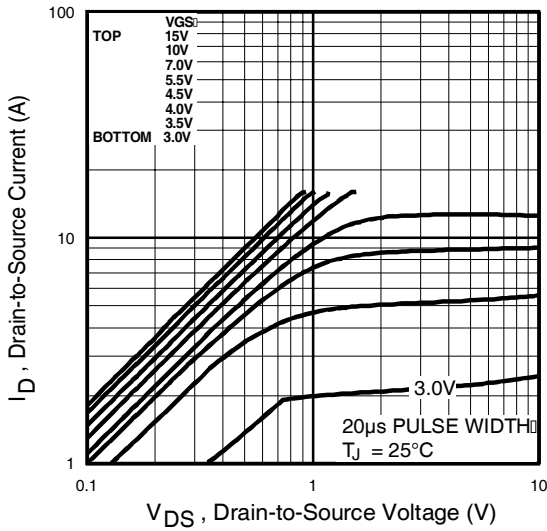


Fig 1. Typical Output Characteristics

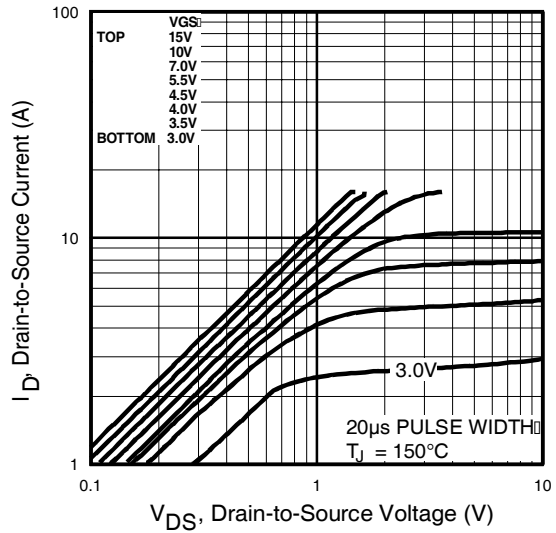


Fig 2. Typical Output Characteristics

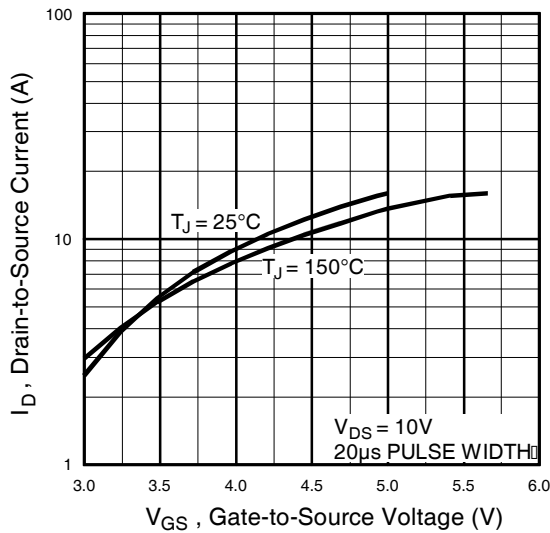


Fig 3. Typical Transfer Characteristics

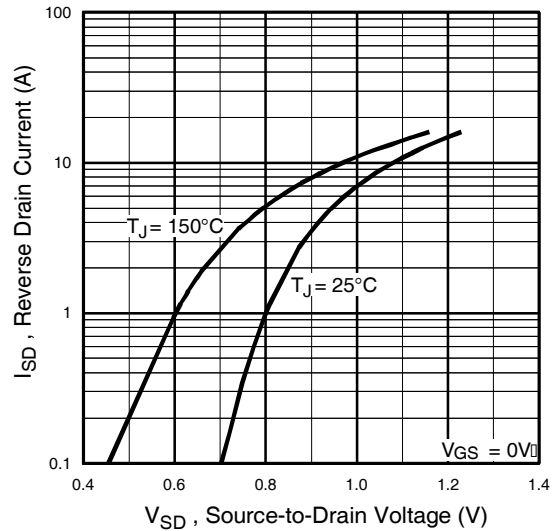
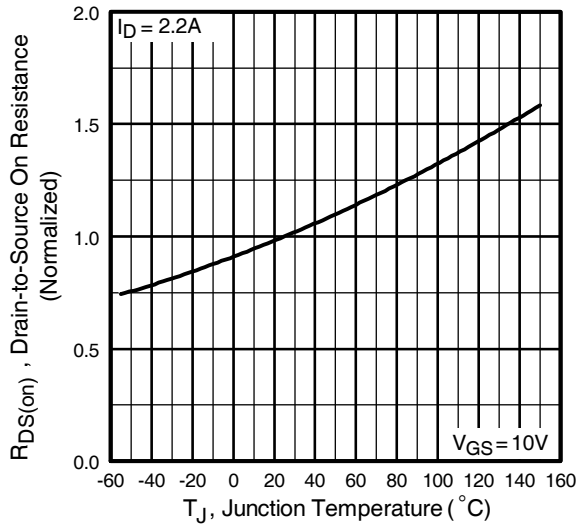
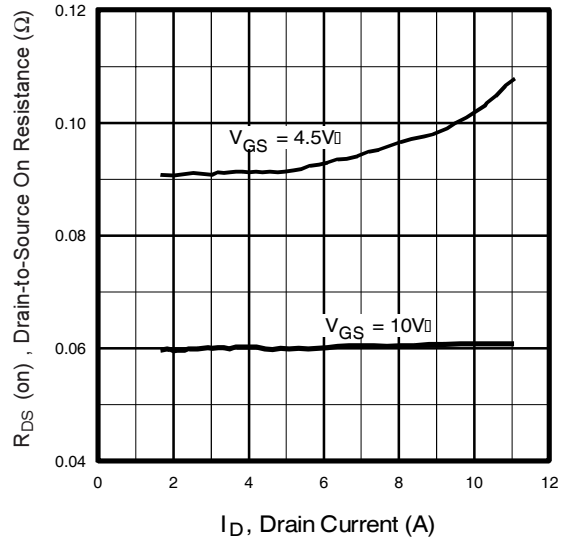


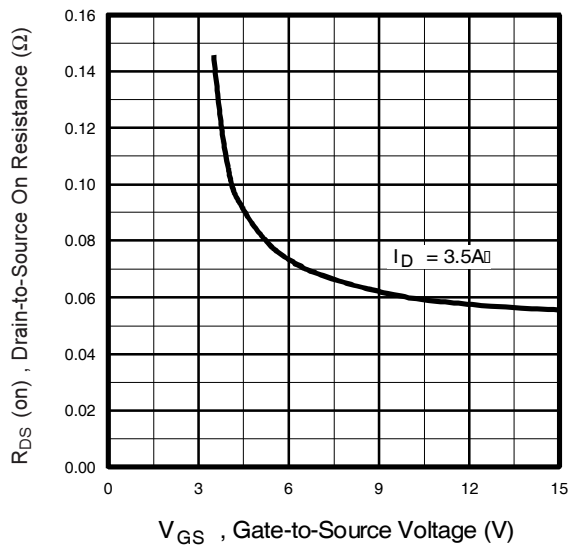
Fig 4. Typical Source-Drain Diode Forward Voltage



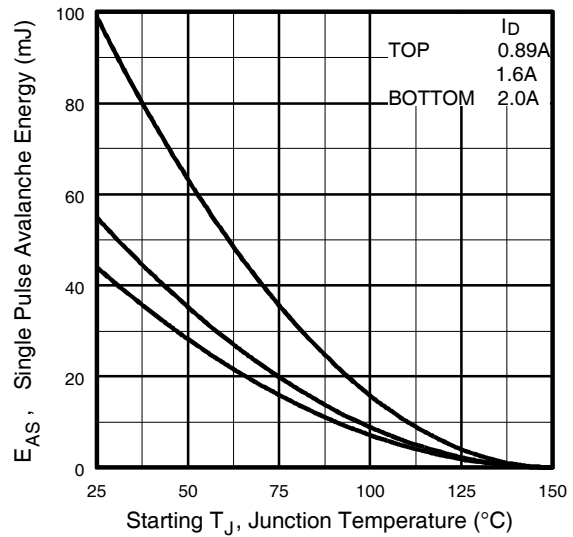
**Fig 5.** Normalized On-Resistance Vs. Temperature



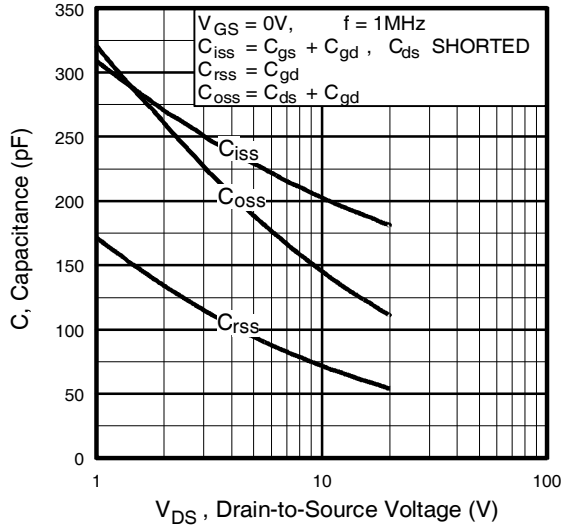
**Fig 6.** Typical On-Resistance Vs. Drain Current



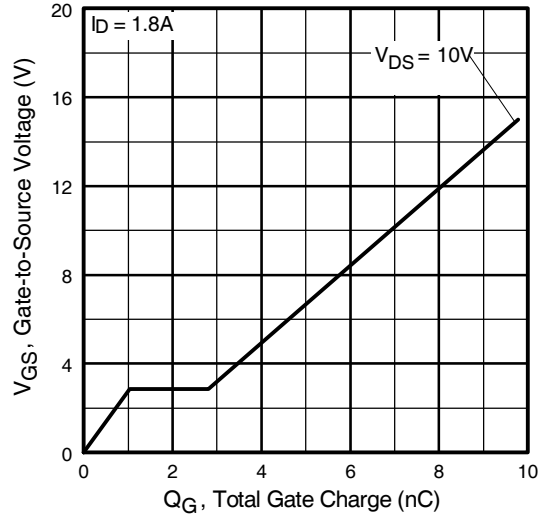
**Fig 7.** Typical On-Resistance Vs. Gate Voltage



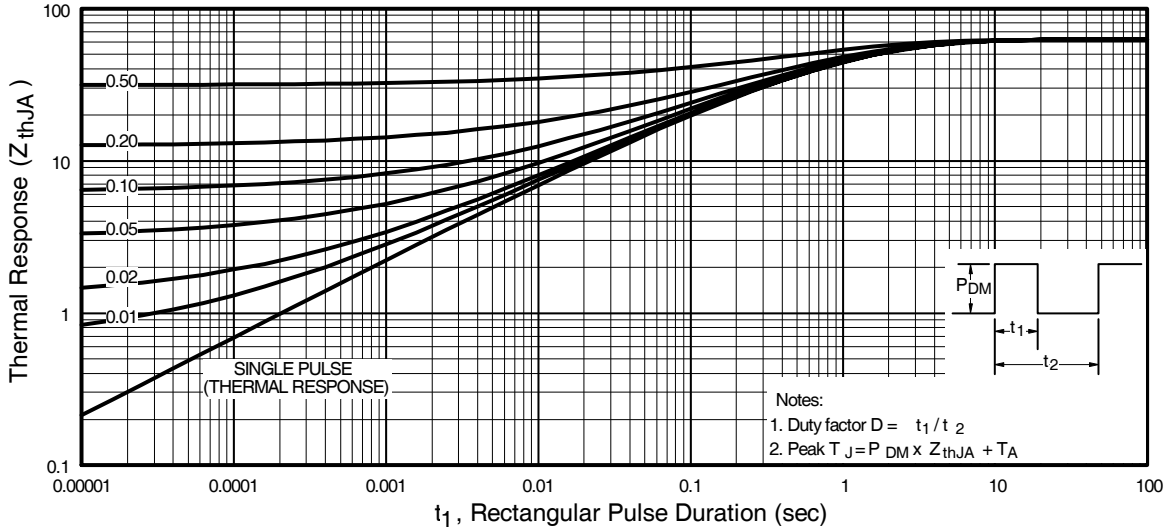
**Fig 8.** Maximum Avalanche Energy Vs. Drain Current



**Fig 9.** Typical Capacitance Vs. Drain-to-Source Voltage



**Fig 10.** Typical Gate Charge Vs. Gate-to-Source Voltage



**Fig 11.** Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

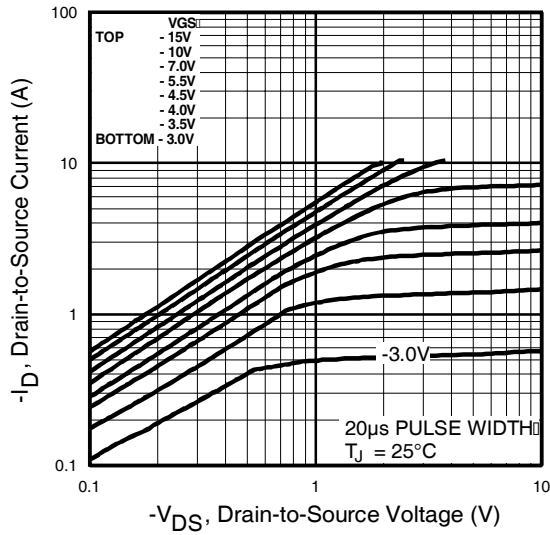


Fig 12. Typical Output Characteristics

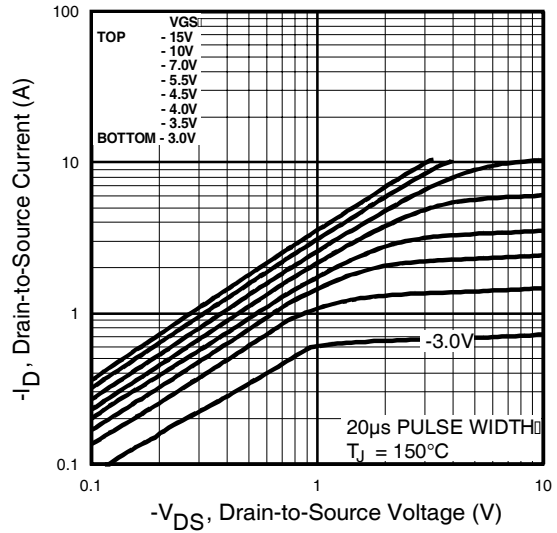


Fig 13. Typical Output Characteristics

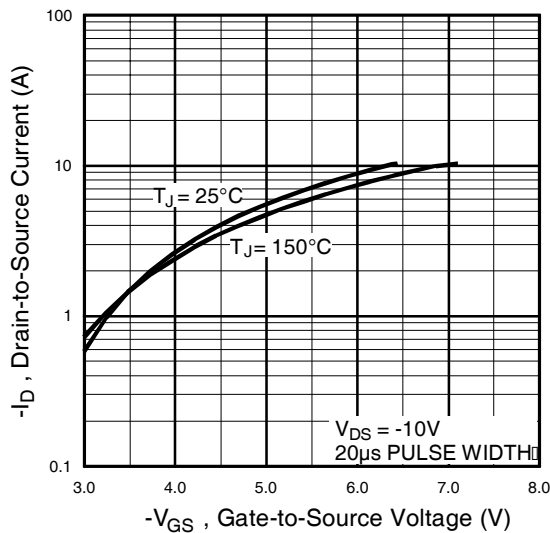


Fig 14. Typical Transfer Characteristics

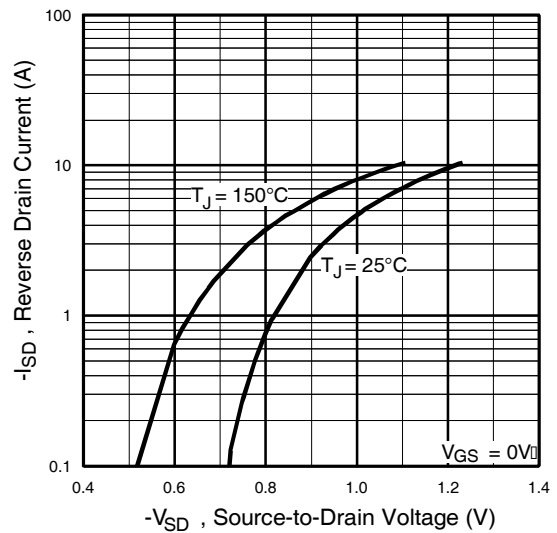
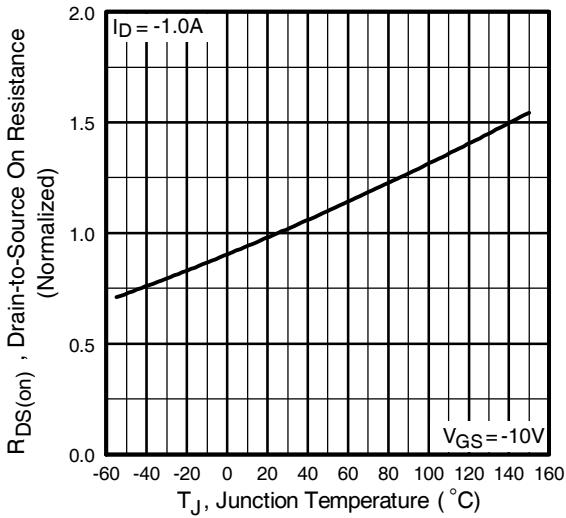
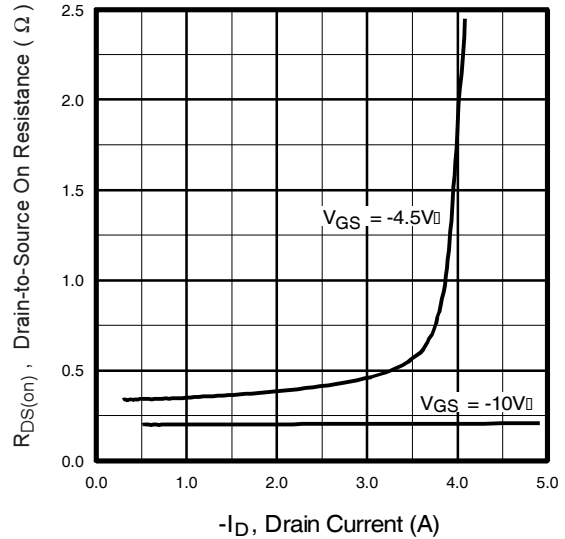


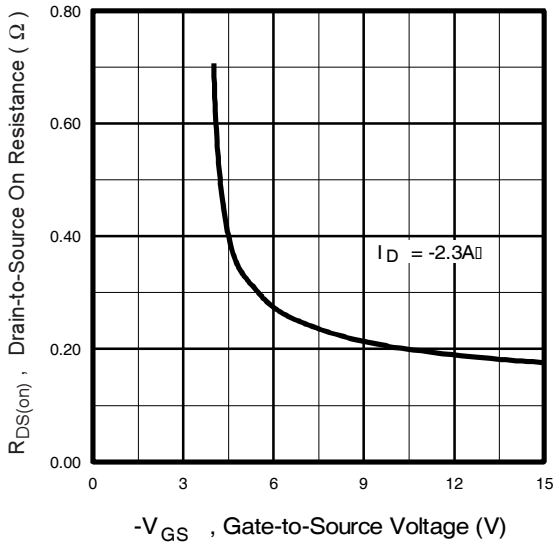
Fig 15. Typical Source-Drain Diode Forward Voltage



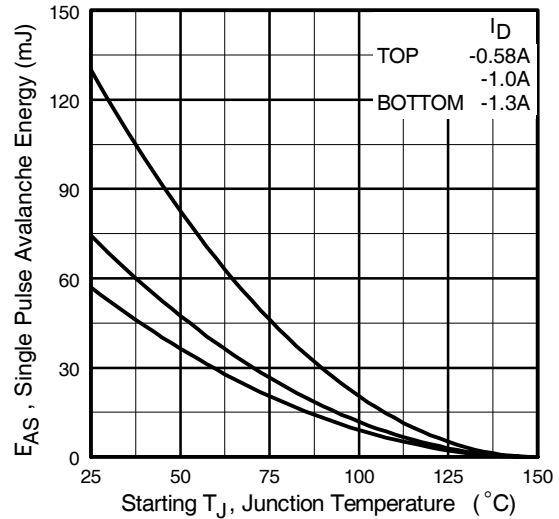
**Fig 16.** Normalized On-Resistance Vs. Temperature



**Fig 17.** Typical On-Resistance Vs. Drain Current



**Fig 18.** Typical On-Resistance Vs. Gate Voltage

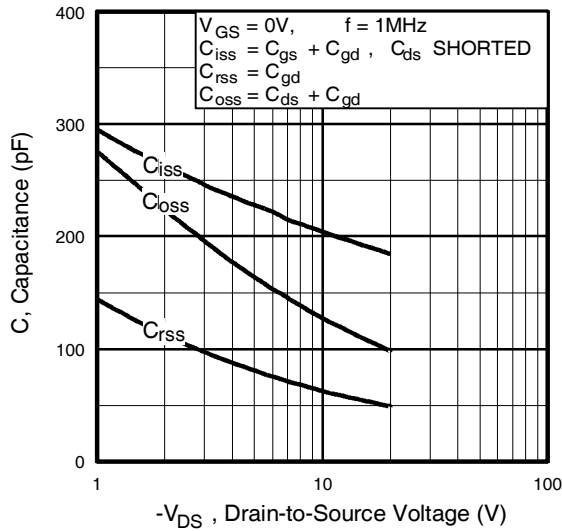


**Fig 19.** Maximum Avalanche Energy Vs. Drain Current

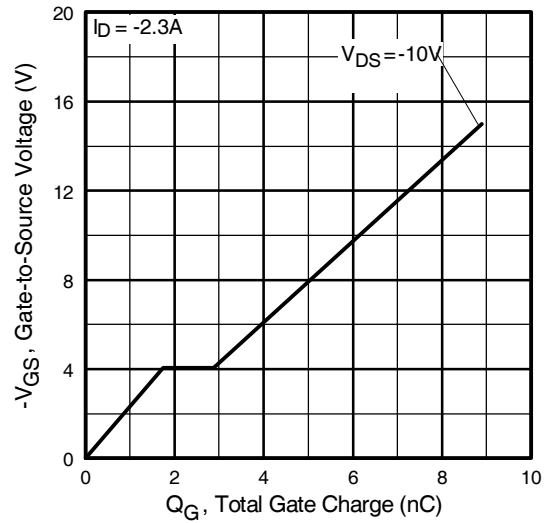
# IRF9952QPbF

P-Channel

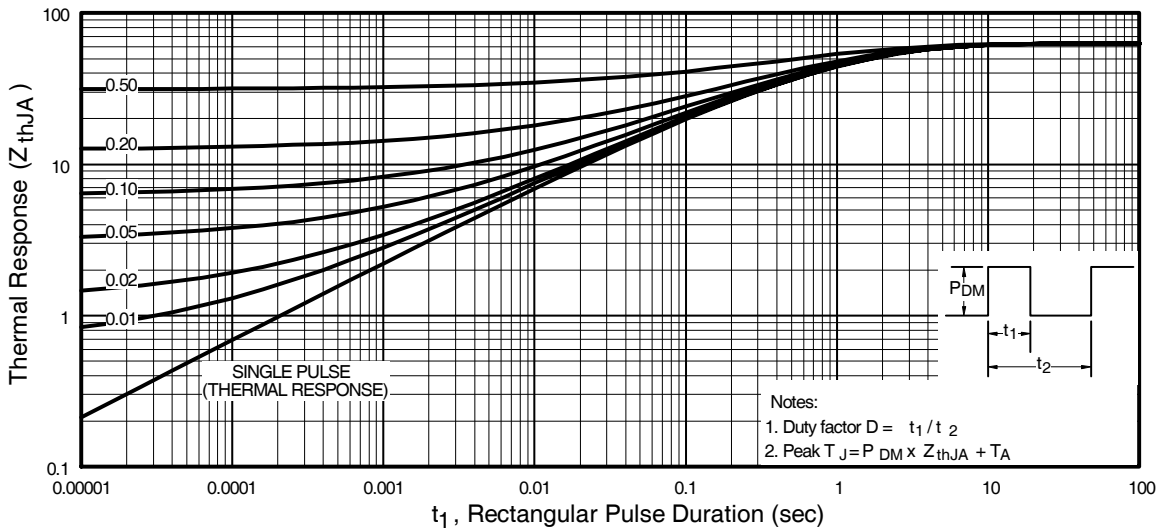
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**Fig 20.** Typical Capacitance Vs. Drain-to-Source Voltage



**Fig 21.** Typical Gate Charge Vs. Gate-to-Source Voltage

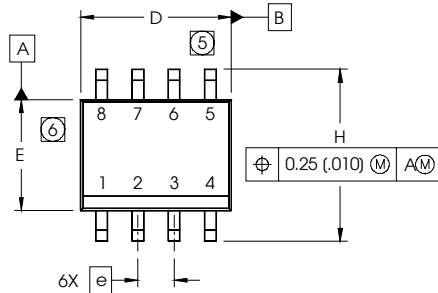


**Fig 22.** Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

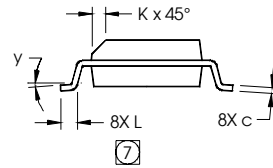
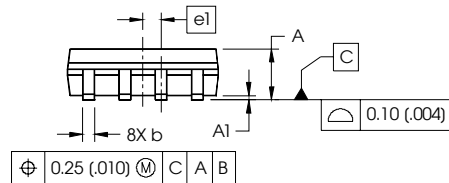


## SO-8 Package Outline

Dimensions are shown in millimeters (inches)



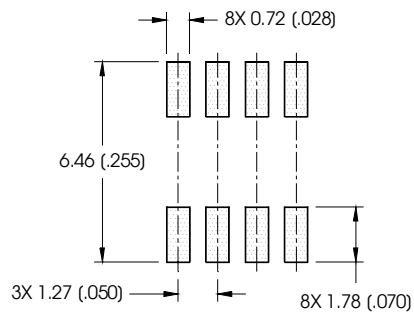
DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.0532	.0688	1.35	1.75
A1	.0040	.0098	0.10	0.25
b	.013	.020	0.33	0.51
c	.0075	.0098	0.19	0.25
D	.189	.1968	4.80	5.00
E	.1497	.1574	3.80	4.00
e	.050 BASIC		1.27 BASIC	
e1	.025 BASIC		0.635 BASIC	
H	.2284	.2440	5.80	6.20
K	.0099	.0196	0.25	0.50
L	.016	.050	0.40	1.27
y	0°	8°	0°	8°



**NOTES:**

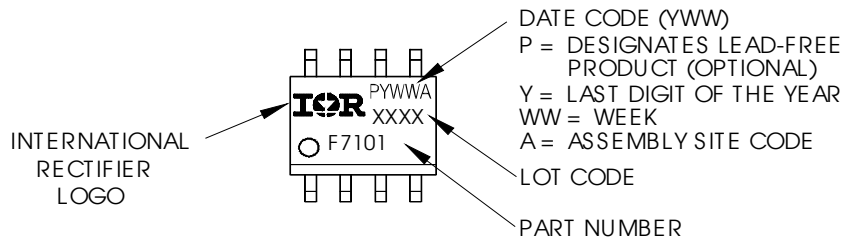
1. DIMENSIONING & TOLERANCING PER ASME Y14.5M-1994.
2. CONTROLLING DIMENSION: MILLIMETER
3. DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
4. OUTLINE CONFORMS TO JEDEC OUTLINE MS-012AA.
- ⑤ DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS. MOLD PROTRUSIONS NOT TO EXCEED 0.15 (.006).
- ⑥ DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS. MOLD PROTRUSIONS NOT TO EXCEED 0.25 (.010).
- ⑦ DIMENSION IS THE LENGTH OF LEAD FOR SOLDERING TO A SUBSTRATE.

**FOOTPRINT**



## SO-8 Part Marking

EXAMPLE: THIS IS AN IRF7101 (MOSFET)



**Notes:**

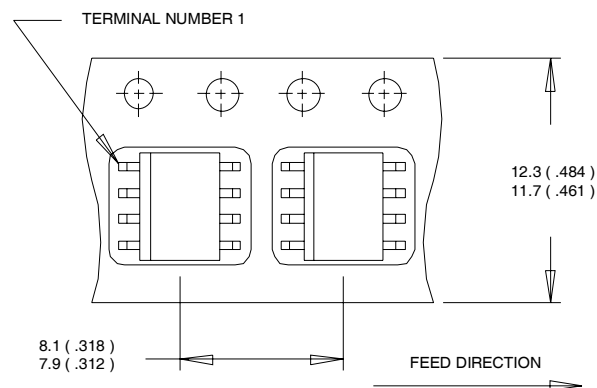
1. For an Automotive Qualified version of this part please see <http://www.irf.com/product-info/autol>
2. For the most current drawing please refer to IR website at <http://www.irf.com/package/>

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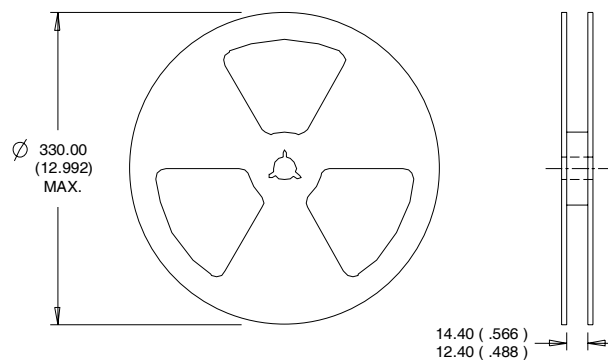
## SO-8 Tape and Reel

Dimensions are shown in millimeters (inches)



### NOTES:

1. CONTROLLING DIMENSION : MILLIMETER.
2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS(INCHES).
3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



### NOTES :

1. CONTROLLING DIMENSION : MILLIMETER.
2. OUTLINE CONFORMS TO EIA-481 & EIA-541.

Data and specifications subject to change without notice.  
This product has been designed and qualified for the Industrial market.  
Qualification Standards can be found on IR's Web site.

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